Integrated double low-side switch, high-side/LED driver, hall supply, wake-up inputs and LIN communication with embedded MCU (32kB Flash)

## Automotive Power



Never stop thinking



### **Table of Contents**

### <span id="page-1-0"></span>**Table of Contents**





### **Table of Contents**





### **Integrated double low-side switch, high-side/LED driver, hall supply, wake-up inputs and LIN communication with embedded MCU (32kB Flash)**



### <span id="page-3-0"></span>**1 Overview**

### **Relay Driver - System Basis Chip**

- Low-Dropout Voltage Regulator (LDO)
- **LIN Transceiver**
- Standard 16-bit SPI-Interface
- $2 \times$  Low-Side Switches, e.g. as Relay Driver
- $2 \times$  Supply e.g. for Hall Sensor Supply / LED Driver
- $5 \times$  High-Voltage Wake-Up Inputs
- Programmable. Window Watchdog & Power Saving Modes
- Power-On and Undervoltage Reset Generator
- Overtemperature Protection
- **Short Circuit Protection**

### **8-bit Microcontroller**

- Compatible to 8051 μC Core
- Two clocks per machine cycle
- 12 kByte Boot ROM for test and Flash routines
- LIN Bootloader (Boot ROM)
- 256 Byte RAM / 1.5 kByte XRAM
- 32 kByte Flash Memory for Program Code & Data
- On-Chip Oscillator
- Power Saving Modes (slow-down & idle mode)
- Programmable Watchdog Timer
- 10-bit A/D Converter, e.g. for Temperature &  $V_{\text{bat}}$ -Measurement
- Three 16-bit Timers & Capture/Compare Unit
- General Purpose I/Os, e.g. with PWM Functionality
- On-Chip Debug Support (JTAG)
- UART and Synchronous Serial Channel (SSC respective SPI)
- Multiply-Divide-Unit (MDU)

### **General Characteristics**

- Package PG-DSO-28-38
- Temperature Range  $T$ <sub>J</sub>: -40 °C up to 150 °C
- Green Package (RoHS compliant)
- AFC Qualified





**PG-DSO-28-38**

**TLE7826G**



#### **Overview**

### **Description**

This single-packaged solution incorporates an 8-bit state-of-the-art microcontroller compatible to the standard 8051 core with On-Chip Debug Support (OCDS), and a System-Basis-Chip (SBC). The SBC is equipped with LIN transceiver, low-dropout voltage regulator (LDO) as well as two low-side switches (relay driver) and a high-side driver e.g. for driving LEDs. An additional supply, e.g. to supply hall sensors (TLE 4966) is also available.

For Micro Controller Unit (MCU) supervision and additional protection of the circuit a programmable window watchdog circuit with a reset feature, supply voltage supervision and integrated temperature sensor is implemented on the SBC.

Microcontroller and LIN module offer low power modes in order to support terminal 30 connected automotive applications. A wake-up from the low power mode is possible via a LIN bus message or wake-up inputs.

This integrated circuit is realized as Multi-Chip-Module (MCM) in a PG-DSO-28-38 package, and is designed to withstand the severe conditions of automotive and industrial applications.

*Note: A detailed description of the 8-bit microcontroller XC885 can be found in a dedicated Userís Manual and Data Sheet.*



**Block Diagram**

### <span id="page-5-0"></span>**2 Block Diagram**





**Pin Definitions and Functions**

<span id="page-6-0"></span>

**Figure 2 Pin Configuration**





### **Pin Definitions and Functions**





### **Pin Definitions and Functions**





**Figure 3 Pinout and Module Interconnects**



### <span id="page-9-4"></span><span id="page-9-0"></span>**4 Operating Modes**

The TLE7826G incorporates several SBC operating modes, that are listed in **[Table 1](#page-9-2)**.



### <span id="page-9-2"></span>**Table 1 SBC Operating Modes**

1) WD "off" when voltage-regulator output current below "watchdog disable current threshold"

<span id="page-9-1"></span>2) WD default "off" in SBC Stop / Sleep Mode; WD can be active in order to generate period wake-ups of SBC

<span id="page-9-3"></span>3) "ON / OFF" state is inherited from previous operating mode ("OFF" after POR and RESET)

The System-Basis-Chip (SBC) offers several operation modes that are controlled via three mode select bits MS0, MS1 and MS2 within the SPI: SBC Active, Sleep and Stop mode, as well as LIN Receive-Only mode.

An overview of the operating modes and the operating mode transitions is indicated in **[Figure 4](#page-10-2)** below.

*Note: It is possible to directly change from Stand-By to Stop or Sleep mode, however this might result in a higher current consumption (~200µA). The higher current consumption will occur in case of a power up and in case of a LIN wake-up from Stop and Sleep mode. To avoid this conditions its recommended to prior set Active mode before changing to Stop or Sleep mode.*



**Operating Modes**



<span id="page-10-2"></span>**Figure 4 State Diagram "SBC Operation Modes"** 

### <span id="page-10-0"></span>**4.1 SBC Standby Mode**

After powering-up the SBC or wake-up from power-saving, it automatically starts-up in **SBC Standby Mode**, waiting for the microcontroller to finish its startup and initialization sequences. However, this mode cannot be selected via SPI command. From this transition mode the SBC can be switched via SPI command into the desired operating mode. All modes are selected via SPI bits or certain operation conditions, e.g. external wake-up events.

### <span id="page-10-1"></span>**4.2 SBC Active Mode**

The **SBC Active Mode** is used to transmit and receive LIN messages and provides the sub-mode "LIN Sleep".



### <span id="page-11-0"></span>**4.3 SBC Active Mode "LIN Sleep"**

In **SBC Active Mode "LIN Sleep"** the SBC's current consumption is reduced by disabling the LIN transceiver. This also means that the internal pull-up resistor of the LIN transceiver is turned off in SBC Active Mode "LIN Sleepî. During this mode the LIN transceiver remains its wake-up capability in order to react on a remote frame or wake-up pulse (specified in LIN Specification V2.0) from the master node or other slave nodes. In case of a wakeup event via LIN message the (internal) RxD is pulled "low" and the "bus wake-up bit" within the SPI status word is set. However, the LIN transceiver needs to be activated by switching to "SBC Active Mode".

### <span id="page-11-1"></span>4.4 LIN Receive-Only Mode ("LIN RxD-Only")

The LIN Receive-Only Mode ("LIN RxD-Only") is designed for a special test procedure to check the bus connections. **[Figure 5](#page-11-2)** shows a network consisting of 5 nodes. Node 1 is the LIN master node, the others are LIN slave nodes. If the connection between node 1 and node 3 shall be tested, the nodes 2, 4 and 5 are switched into LIN Receive-Only Mode. Node 1 and node 3 are in Active Mode. If node 1 sends a message ("remote frame"), node 3 is the only node which is physically able to reply to the remote frame. The other nodes have their outputs drivers disabled.

The main difference between the **SBC Active Mode** and the **LIN Receive-Only Mode** is that the LIN transmit stage is automatically turned-off in LIN Receive-Only-Mode. However, the LIN receiver is still active in both modes.



<span id="page-11-2"></span>Figure 5 Network Diagram "LIN Receive-Only Mode"



### <span id="page-12-0"></span>**4.5 Power Saving Modes**

### <span id="page-12-1"></span>**4.5.1 SBC Sleep Mode**

During **SBC Sleep Mode** (see **[Figure 6](#page-12-2)**), the lowest power consumption is achieved, by having its main voltage regulator switched-off. As the microcontroller cannot be supplied, the integrated window watchdog can be disabled in Sleep Mode via a dedicated SPI control bit. However, it can be turned-on for periodically waking-up the system, e.g. ECU, by generating a reset and automatically switching to SBC Standby Mode.

This mode is entered via SPI command, and turns-off the integrated LIN bus transceiver, main voltage regulator as well as all switches. Upon a voltage level change at the monitoring / wake-up pins or by LIN message the SBC Sleep Mode will be terminated and the SBC Standby Mode will automatically be entered (turning-on the LDO).

*Note: Upon a wake-up via LIN message the (internal) RxD signal stays "low" until mode switch.* 

- *Note: If the Window Watchdog was not enabled in Sleep Mode the Window Watchdog starts after wake-up with a ìlong open windowî in SBC Standby Mode.*
- *Note: In Sleep Mode with activated watchdog (see Table 2 "SPI Input Data Bits" on Page 21) the oscillator remains turned on.*



<span id="page-12-2"></span>**Figure 6 State Diagram "SBC Sleep Mode"** 



### <span id="page-13-0"></span>**4.5.2 SBC Stop Mode**

The **SBC Stop Mode** has the advantage of reducing the current consumption to a minimum, while supplying the microcontroller with its quiescent current during its power saving mode ("Stop"). This mode is entered via SPI command, and turns-off the integrated bus transceivers and respective termination, but the voltage regulator for the microcontroller supply remains active. A microcontroller in a power saving mode has the advantage over a turned-off microcontroller to have a reduced reaction time upon a wake-up event.

A voltage level change at the monitoring/wake-up pins will, in contrast to the behavior in Sleep Mode, generate a signal that indicates the wake-up event at the microcontroller in Power-Down Mode. This is realized via an interconnect from the SPI of the SBC [DO] to the microcontroller [P1.4]. In case the wake-up event was a LIN message, the respective RxD pin of the SBC and the SPI Data Out [DO] will be pulled "low". RxD is pulled "low" until mode switch, while DO stays "low" for two internal SBC cycles. (The microcontroller itself has to take care of switching SBC modes after a wake-up event notification (see **[Figure 7](#page-13-1)**).)

*Note: The window watchdog is automatically disabled once the LDO output current goes below a specified ìwatchdog current thresholdî, unless the SPI setting ìWD On/Offî prevents this (see* **[Figure 10](#page-19-1)***,* **[Watchdog](#page-37-0)  [disable current threshold](#page-37-0)**, **[Table 14](#page-35-1)** and **[ìWindow Watchdog Reset Period Settingsî on Page 23](#page-22-0)**).





<span id="page-13-1"></span>**Figure 7 State Diagram "SBC Stop Mode"** 



### <span id="page-14-0"></span>**4.5.3 SBC Stop Mode with Cyclic Wake**

The SBC Stop Mode has the advantage of reducing the current consumption to a minimum, while supplying the microcontroller with its quiescent current during its power saving mode ("Stop"). This mode is entered via SPI command, and turns-off the integrated LIN bus transceiver, but the voltage regulator remains active.

The SBC periodically generates a wake-up "low" pulse at DO ("interconnect signal") that is connected to an interrupt input [P1.4] of the microcontroller. This period can be defined via the "cyclic wake period" bit field within the SPI register. This pulse at DO has a length of **two** internal SBC cycles.

In case of a detected wake-up event via LIN message or any of the MONx pins, DO stays "low" until the first valid SPI command.

*Note: The window watchdog is automatically disabled once the LDO output current goes below a specified ìwatchdog current thresholdî, unless the SPI setting ìWD On/Offî prevents this (see* **[Figure 10](#page-19-1)***).*

*Note: A wake-up event via LIN message or via MONx inputs can happen independently of the cyclic wake phase.*

*Note: The Window Watchdog starts with a "long open window" after a mode switch, e.g. to SBC Active Mode.* 



**Figure 8 State Diagram "SBC Stop Mode with Cyclic Wake"** 



**LIN Transceiver**

### <span id="page-15-0"></span>**5 LIN Transceiver**

The TLE7826G offers a LIN transceiver, which is compatible to ISO9141 and certified according to LIN Specification 1.3 and 2.0 "Physical Layer". The transceiver has a pull-up resistor of 30 kΩ implemented and is protected against short to battery and short to GND.

The LIN transceiver has an implemented wake-up capability during operation in power saving modes. In Stop Mode a wake-up event is indicated via (internal) RxD and DO signals, that are pulled "low". Out of Sleep Mode a wake-up event causes an automatic transition into Standby Mode and the (internal) RxD and DO signals are pulled ìlowî. If the TxD input is pulled low for longer than the TxD dominant timeout the TxD input is ignored and the LIN bus goes back to recessive state. This fail-safe feature in case of a permanent low TxD signal recovers if the TxD pin is high for TxD dominant timeout recovery time.

For LIN automotive applications in the United States a dedicated mode by the name "Low Slope Mode" can be used. This mode reduces the maximum data transmission rate of 20 kBaud to 10.4 kBaud by switching to a different slew rate. By using this mode the EM noise emission can be reduced.



#### **ADC Measurement Interface**

### <span id="page-16-0"></span>**6 ADC Measurement Interface**

The SBC measurement interface comprises a battery measurement unit (high voltage input  $V_{\text{bat-sense}}$ ) and an onchip temperature sensor. A multiplexer is used to select the desired input channel that is connected to the ADC of the  $\mu$ C. This multiplexer is controlled via the SPI interface. Also, the reference voltage  $V_{ARFF}$  is provided by the SBC. The  $V_{\text{bat sense}}$  input must be protected against voltage transients, like ISO pulses by a resistor in series to terminal 30.



**Figure 9 Simplified Block Diagram of ADC Measurement Interface**

### <span id="page-16-1"></span>**6.1 Voltage Measurement**

The input voltage is filtered and scaled down to the input voltage range of the ADC converter. The voltage measurement output code of the ADC can be calculated using the following equation, where  $V_{\text{SENS}}$  is the voltage at the pin  $V_{\text{BAT} \text{ SENSE}}$  and N the resolution of the ADC:

$$
C_{\text{VSENS}} = \text{round}\left[\frac{V_{\text{SENS}}}{V_{\text{AREF}}} \frac{1}{8} (2^N - 1)\right], \quad \text{OV} \leq V_{\text{SENS}} \leq V_{\text{bat-fs}} \tag{1}
$$

The input voltage corresponding to the ADC output code C<sub>VSENS</sub> can be calculated with the following equation:

$$
V_{\text{SENS}} = \frac{8 \times V_{\text{AREF}}}{2^{N} - 1} \times C
$$
 (2)

### <span id="page-16-2"></span>**6.1.1 Voltage Measurement Calibration Concept**

Best measurement accuracy can be obtained by applying the calibration function:

$$
C_{\text{VSENSCAL}} = \text{round}[c_1(C_{\text{VSENS}} - c_0)] \tag{3}
$$

 $C_{\text{VSENS}}$  represents the ADC output code for the analog input voltage at the pin  $V_{\text{BAT} SENSE}$ . The correction coefficients  ${\mathsf c}_1$  and  ${\mathsf c}_0$  correct for slope variations and offset errors of the measurement transfer function.

During the production test these calibration figures are calculated and stored in the flash memory of the microcontroller.



#### **ADC Measurement Interface**

Further details on the implementation of the calibration function and location of the calibration figures in Flash memory can be found in a dedicated application note. The voltage measurement target parameters can be found in "ADC Battery Voltage Measurement Interface, VBAT\_SENSE" on Page 44.

### <span id="page-17-0"></span>**6.2 Temperature Measurement**

In the temperature measurement mode the typical internal analog output voltage of the on-chip temperature sensor can be described with the first order approximation:

$$
V_A \approx m_0 - m_1 \times T_j \tag{4}
$$

Where:

- $\bullet$   $T_{\rm j}$  is the junction temperature in Kelvin
- $m_{\text{o}}$ and  $m_{\text{1}}$  are typical linear fitting parameters (see Table "ADC Temperature Measurement Interface" on Page 44)

The output code of the ADC is given by the following equation, where  $V_{\text{AREF}}$  and N denote the ADC reference voltage and the resolution of the ADC:

$$
C_{\rm A} = \text{round}\bigg[V_{\rm A}(T_{\rm j}) \times \frac{(2^{\rm N}-1)}{V_{\rm AREF}}\bigg], \ V_{\rm A} \le V_{\rm AREF} \tag{5}
$$

The junction temperature  $T_\mathrm{J}$  corresponding to the output code  $C_\mathsf{A}$  is given by:

$$
T_{\mathbf{j}} = \frac{1}{m_1} \Big[ m_0 - \frac{C_A(T_{\mathbf{j}}) \times V_{\text{AREF}}}{2^N - 1} \Big] \tag{6}
$$

273.15 °C need to be subtracted to convert  $T_{\rm j}$  [K] into Centigrade Scale [°C].

The temperature measurement target parameters can be found in<sup>a</sup> ADC Temperature Measurement Interface<sup>39</sup> **[on Page 44](#page-43-1)**.

### <span id="page-17-1"></span>**6.2.1 Temperature Measurement Calibration Concept**

Best measurement accuracy can be obtained by applying the calibration function:

$$
T_{\text{CAL}} = 586 + f_0 \cdot 2^{-1} - [2^{-2} + f_1 \cdot 2^{-10}] C_A(T_j)
$$
\n(7)

The calibration coefficients  $f_{0/1}$  are computed during the production test and stored in the flash memory of the microcontroller.

The selection between battery voltage and temperature measurement is done via SPI bit (see "SPI (Serial **Peripheral Interface)**" on Page 20).

Further details on the implementation of the calibration function and location of the calibration figures can be found in a dedicated application note.



### **Low Dropout Voltage Regulator**

### <span id="page-18-0"></span>**7 Low Dropout Voltage Regulator**

The Low Drop-Out Voltage Regulator (LDO) has mainly been integrated in the TLE7826G in order to supply the integrated microcontroller and several modules of the SBC.

*Note: The LDO is not intended to be used as supply for external loads. However, it might be used as supply for small external loads (see Table 13 "Operating Range" on Page 35).* 

In the event of a short circuit condition at the  $V_{cc}$  pin, a shutdown/reset of the TLE7826G may occur due to overcurrent condition. This maximum output current for external loads is specified in the electrical characteristics. The voltage regulator output is protected against overload and overtemperature.

An external reverse current protection is required at the pin  $V_{\bf S}$  to prevent the output capacitor at  $V_{\bf CC}$  from being discharged by negative transients or low  $V_\mathbf{S}$  voltage.



### <span id="page-19-0"></span>**8 SPI (Serial Peripheral Interface)**

Control and status information between SBC and  $\mu$ C is exchanged via a digital interface, that is called "serial peripheral interface" (SPI) on the SBC side, and "synchronous serial channel" (SSC) on the μC side. The 16-bit wide Programming or Input Word of the SBC (see **[Table 2](#page-20-0)** to [Table 8](#page-22-0)) is read in via the data input DI (with "LSB first"), which is synchronized with the clock input CLK supplied by the  $\mu$ C. The Diagnosis or Output Word appears synchronously at the data output DO (see **[Table 9](#page-22-1)**).

The transmission cycle begins when the chip is selected by the Chip Select Not input CSN ("low" active). After the CSN input returns from L to H, the word that has been read in becomes the new control word. The DO output switches to tri-state status at this point, thereby releasing the DO bus for other usage.

The state of DI is shifted into the input register with every falling edge on CLK. The state of DO is shifted out of the output register after every rising edge on CLK. The number of received input clocks is supervised by a modulo-16 operation and the Input/Control Word is discarded in case of a mismatch.

This error is flagged by a "high" at the data output pin DO (interconnect to  $\mu$ C: P1.4) of the following SPI output word before the first rising edge of the clock is received. Additionally the logic level of DO will be "OR-ed" with the logic level of DI (P1.3).

*Note: After wake-up from low-power modes the device needs to be set to Active Mode first before switches like LS1, LS2, Supply Output and LED Driver can be turned on with the second SPI command.*



<span id="page-19-1"></span>**Figure 10 16-Bit SPI Input Data / Control Word**

<span id="page-20-0"></span>

### **Table 3 Mode Selection Bits**



### **Table 4 Configuration Selection Bits**







### <span id="page-21-0"></span>**Table 5 General & Integrated Switch Configuration**

1)  $i1" = ON / enable, i0" = OFF / disable$ 

2)  $i'1" = ON$ ,  $i'0" = OFF$ 

### **Table 6 Cyclic Wake & Window Watchdog Period Settings1)2)**



1)  $i'1" = ON$ ,  $i'0" = OFF$ 

2) Cyclic wake and window watchdog period settings see Table 7 "Cyclic Wake Period Settings (Stop Mode only)" on **[Page 23](#page-22-2)**



### **SPI (Serial Peripheral Interface)**

<span id="page-22-2"></span>

### <span id="page-22-0"></span>**Table 8 Window Watchdog Reset Period Settings**



### <span id="page-22-1"></span>**Table 9 SPI Output Data**





### Table 9 SPI Output Data (cont'd)



1)  $i'1" = ON / enable, '0" = OFF / disable, OC = overcurrent, UV = undervoltage,$ 

OT = overtemperature (temp. shut-down)

2)  $i=1$  = ON,  $i=0$  = OFF, OC = overcurrent, UV = undervoltage, OT = overtemperature (temp. shut-down)

3) Becomes valid after start-up time for voltage monitoring

4) Voltage monitoring not active in SBC Standby Mode

5) This bit needs to be read twice to indicate an undervoltage condition (only for  $V_{\bf S}$  ramping down - bit15 set to "1")



### <span id="page-23-0"></span>**Table 10 Diagnostic, Protection and Safety Functions**



### **SPI (Serial Peripheral Interface)**



### **Table 10 Diagnostic, Protection and Safety Functions** (contíd)

1) WD (Window) Watchdog

2) OC overcurrent detection

3) OT overtemperature detection



### **Reset Behavior and Window Watchdog**

### <span id="page-25-0"></span>**9 Reset Behavior and Window Watchdog**

The SBC provides three different resets:

- V<sub>INT</sub>-UV: reset of SBC upon undervoltage detection at *internal* supply voltage
- $V_{cc}$ **-UV:** reset of SBC upon undervoltage detection at supply voltage ( $V_{cc}$ )
- **Watchdog:** reset of SBC caused by integrated window watchdog

Should the internal supply voltage become lower than the internal threshold the  $V_{\text{INT}}$ -Fail SPI bit will be reset in order to indicate the undervoltage condition  $(V_{\text{INT}}$ -UV). All other SPI settings are also reset by this condition. The  $V_{\text{INT}}$ -Fail feature can also be used to give an indication that the system supply was disconnected and therefore a pre-setting routine of the microcontroller has to be started.

When the  $V_{\text{CC}}$  voltage falls below the reset threshold voltage  $V_{\text{RTx}}$  for a time duration longer than the filter time  $t_{RR}$ the reset output is switched LOW and will be released after a programmable delay time (default setting for Power-On-Reset) when  $V_{cc}$  >  $V_{RTx}$ . This is necessary for a defined start of the microcontroller when the application is switched on after Power-On-Reset. As soon as an undervoltage condition of the output voltage ( $V_{\text{CC}}$  <  $V_{\text{RTx}}$ ) appears, the reset output is switched LOW again ( $V_{cc}$ -UV). The reset delay time can be shortened via SPI bit. Please refer to **[Figure 17](#page-46-0)**.



### <span id="page-25-1"></span>**Table 11 Reset Behavior SBC**

After the above described delayed reset (LOW to HIGH transition at RESET pin) the **window watchdog** circuit is started by opening a long open window in SBC Standby Mode. The long open window allows the microcontroller to run its initialization sequences and then to trigger the watchdog via the SPI. Within the long open window period a watchdog trigger is detected as a write access to the "window watchdog period bit field" within the SPI control word. The trigger is accepted when the CSN input becomes HIGH after the transmission of the SPI word.

A correct watchdog trigger results in starting the window watchdog by opening a closed window with a width of 50% of the selected window watchdog period. This period, selected via the SPI window watchdog timing bit field, is programmable in a wide range. The closed window is followed by an open window with a width of 50% of the selected period. The microcontroller has to service the watchdog by periodically writing to the window watchdog timing bit field. This write access has to meet the open window. A correct watchdog service immediately results in starting the next closed window.

Should the trigger signal not meet the open window a watchdog reset is generated by setting the reset output low. Then the watchdog again starts by opening a long open window. In addition, a "window watchdog reset flag" is set within the SPI to monitor a watchdog reset. For fail safe reasons the TLE7826G is automatically switched to SBC Standby mode if a watchdog trigger failure occurs. This minimizes the power consumption in case of a permanent faulty microcontroller. This "window watchdog reset flag" will be cleared by any access to the SPI.

When entering a low power mode the watchdog can be requested to be enabled via an SPI bit. In SBC Stop Mode the watchdog is only turned off once the current consumption at  $V_{\text{CC}}$  falls below the "watchdog current threshold".



### <span id="page-26-0"></span>10 Monitoring / Wake-Up Inputs MON1 ... 5 and Wake-Up Event **Signalling**

In addition to a wake-up from SBC Stop / Sleep Mode via the LIN bus line it is also possible to wake-up the TLE7826G from low power mode via the monitoring/wake-up inputs. These inputs are sensitive to a transition of the voltage level, either from high to low or vice versa. Monitoring is available in Active Mode and indicates the voltage level of the inputs via SPI status bits.

A positive or negative voltage edge at MONx in SBC Sleep or Stop Mode results in signalling a wake-up event (via SBC [DO] to μC [P1.4] interconnect). After a wake-up via MONx the first transmission of the SPI diagnosis word in SBC Standby mode indicates the wake-up source. Further SPI status word transmissions show the logic level at the monitoring input pins.

*Note: Immediately before switching the TLE7826G into a SBC power saving mode the activated MONx are initialized with the actual logic level detected at the MONx. In case a MONx is deactivated it can neither be used as wake-up source nor can it be used to detect logic levels.*

*However, there should be a minimum delay of three times "CSN high time" (see Table "SPI Data Input Timing1)* on Page 43*)* between activation of MONx and entering a power saving mode.

The monitoring input module consists of an input circuit with pull-up and pull-down current sources to define a certain voltage level with open inputs and a filter function to avoid wake-up events caused by unwanted voltage transients at the module inputs.

At a voltage level at the monitoring pins of  $V_{MON\_th}$  <  $V_{MONx}$  < 5.5 V the pull-up current source becomes active, while at 1 V <  $V_{MONx}$  <  $V_{MON<sub>th</sub>}$  the pull-down sink is activated (see **[Figure 11](#page-26-1)**) guaranteeing stable levels at the monitoring/wake-up inputs. Below and above these voltage ranges the current is minimized to a leakage current (see "Monitoring Inputs MONx" on Page 38).



<span id="page-26-1"></span>**Figure 11 Monitoring Input Block Diagram**







**Figure 12 Monitoring Input Characteristics**



**Low Side Switches**

### <span id="page-28-0"></span>**11 Low Side Switches**

The low side switches LS1 and LS2 have been designed to drive relays, e.g. in window lift applications. The continuous output current is dimensioned for 300mA (each) maximum. In SBC Active and LIN Receive-Only mode the low side outputs can be switched on and off, respectively via an SPI input bit. Protection against overcurrent, overtemperature and overvoltage conditions is integrated in the low-side drivers.

In case of a load current that is exceeding the overcurrent threshold both drivers are switched-off after a filter time. A thermal protection circuit is included as well, and is switching-off the drivers in case the overtemperature threshold is reached. In both cases the SPI diagnostic information is updated accordingly and the ERR interconnect is pulled "low" for **one internal cycle** (see "SBC Oscillator" on Page 37). The drivers have to be re-activated via SPI command. An overvoltage protection has been implemented by active clamping for inductive loads preventing the occurrence of voltage peaks.

Moreover the switches are automatically disabled when a reset or watchdog reset occurs. However, the switches are not automatically switched off in case of an overvoltage condition, e.g. load dump. If a double-failure occurs at the same time causing an overcurrent (OC) or overtemperature (OT) condition, than the LSx are turned off in order to protect the IC.

*Note: In case one LSx is turned off due to an OC / OT condition the second LSx is turned off automatically (bidirectional ERR interconnect pulled "low").* 

The LSx can also be switched off by the microcontroller by pulling the bi-directional ERR interconnect "low" for at least one internal cycle (see "SBC Oscillator" on Page 37).



### **Supply Output for Hall Sensor Supply**

### <span id="page-29-0"></span>**12 Supply Output for Hall Sensor Supply**

The SUPPLY Output is intended to be used as Hall Sensor supply. In SBC Active and LIN Receive-Only mode this output can be switched on and off, respectively via an SPI input bit.

*Note: The SUPPLY Output needs to be turned-off prior to entering SBC Stop Mode via SPI command as it will inherit the "on or off state" from the previous operation mode. In case of entering SBC Sleep Mode it is turned-off automatically.*

This output provides an output voltage limitation and is protected against overcurrent and overtemperature. The protection mechanisms for the low-sides switches also apply for this high-side switch. In case of an overcurrent shutdown the supply output can be re-activated via SPI command. In order to prevent an unintended shut-down due to an overcurrent situation when a capacitive load is connected, a specified blanking time after switching-on has been implemented and is applied directly after activation of this output.



### **High-Side Switch as LED Driver (HS-LED)**

### <span id="page-30-0"></span>**13 High-Side Switch as LED Driver (HS-LED)**

The high side output HS\_LED is intended for driving LEDs or small lamps. This function and the wake-up function via MON5 input are realized on the same pin (MON5/HS\_LED). In SBC Active and LIN Receive-Only mode the high side output can be switched on and off, respectively via an SPI input bit (automatically "off" in SBC Stop Mode).

The high-side driver is protected against overcurrent and overtemperature. The HS-LED is automatically disabled in case of an undervoltage ( $V_{\text{bat}}$ -UV) and overvoltage condition ( $V_{\text{bat}}$ -OV) and can only be re-activated via SPI command. This HS-LED OV/UV feature can be disabled via SPI bit (see Table 5 "General & Integrated Switch **Configuration**" on Page 22).



### **General Purpose I/Os (GPIO)**

### <span id="page-31-0"></span>**14 General Purpose I/Os (GPIO)**

The pins P0.3 / P0.4 / P0.5 and P2.0 / P2.1 provide general purpose functionality, like Hall Sensor inputs, PWM output and capture. GPIOs P0.0, P0.1 and P0.2 are available in user mode only (alternate JTAG functionality). For further information see dedicated XC885 User's Manual and/or Data Sheet.



### **Error Interconnect (ERR)**

### <span id="page-32-0"></span>**15 Error Interconnect (ERR)**

The ERR interconnect provides a bi-directional error signalization. The ERR output (active low) immediately signals that a low side switch LSx has been shut down due to overcurrent or overtemperature condition. If the ERR signal is pulled "low" by the microcontroller for at least one internal cycle (see "SBC Oscillator" on Page 37), the low side switches LS1/LS2 are turned off (see Table 10 "Diagnostic, Protection and Safety Functions" on **[Page 24](#page-23-0)**).



### <span id="page-33-1"></span><span id="page-33-0"></span>**16.1 Absolute Maximum Ratings**

### **Table 12 Absolute Maximum Ratings1)**

 $T_{\rm j}$  = -40 °C to +150 °C; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



<span id="page-33-2"></span>1) Not subject to production test, specified by design.



- *Note: Stresses above the ones listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.*
- *Note: Integrated protection functions are designed to prevent IC destruction under fault conditions described in the*  data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are *not designed for continuous repetitive operation.*

### <span id="page-34-2"></span><span id="page-34-0"></span>**16.2 Functional Range**

### <span id="page-34-3"></span>**Table 13 Operating Range**



### <span id="page-34-5"></span><span id="page-34-1"></span>**16.3 Thermal Resistance**

<span id="page-34-6"></span>

<span id="page-34-4"></span>1) Not subject to production test, specified by design

2) Specified R<sub>thJA</sub> value is according to Jedec JESD51-2,-7 at natural convection on FR4 2s2p board; The Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 2 inner copper layers (2 x 70µm Cu, 2 x 35µm Cu).



### <span id="page-35-0"></span>**16.4 Electrical Characteristics**

### <span id="page-35-1"></span>**Table 14 Electrical Characteristics**

 $V$ <sub>S</sub> = 13.5 V,  $T$ <sub>j</sub> = -40 °C to +150 °C, all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



 $rejection<sup>1</sup>$ 

 $C_{\text{VCC}} = 1 \mu F$ 



### Table 14 Electrical Characteristics (cont'd)

<span id="page-36-0"></span>



### Table 14 Electrical Characteristics (cont'd)

<span id="page-37-2"></span><span id="page-37-1"></span><span id="page-37-0"></span>



### Table 14 Electrical Characteristics (cont'd)





### Table 14 Electrical Characteristics (cont'd)

<span id="page-42-0"></span>



### Table 14 Electrical Characteristics (cont'd)

<span id="page-43-1"></span><span id="page-43-0"></span>



### **Timing Diagrams**

### Table 14 Electrical Characteristics (cont'd)

 $V$ <sub>S</sub> = 13.5 V,  $T$ <sub>j</sub> = -40 °C to +150 °C, all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)



<span id="page-44-1"></span>1) Not subject to production test, specified by design.

2) normal operation continuous current should not exceed 300mA (for each low-side LS1 and LS2)

3) Production testing in 20 kbit/s mode

<span id="page-44-2"></span>4) Tested on wafer level only.

<span id="page-44-0"></span>

**Figure 13 SPI-Data Transfer Timing**



















<span id="page-46-0"></span>**Figure 17 Reset Timing Diagram**





**Figure 18 LIN Dynamic Characteristics Timing Diagram**



### **Application Information**

### <span id="page-48-0"></span>**18 Application Information**

### <span id="page-48-1"></span>**18.1 Application Diagram**

*Note: The following information is given as a hint for the implementation of the device only and shall not be regarded as a description or warranty of a certain functionality, condition or quality of the device*



**Figure 19 Application Diagram**

*Note: This is a very simplified example of an application circuit. The function must be verified in the real application. Note: For inverse-polarity protection / protection against ISO pulses the diode and the 10µF capacitor is required.*

### <span id="page-48-2"></span>**18.2 Hints for Unused Pins**

- SUPPLY: connect to  $V<sub>S</sub>$
- MON1/2/3/4: connect to GND or leave open
- MON5/HS-LED, LIN: leave open



### **Application Information**

### <span id="page-49-0"></span>**18.3 Flash Program Mode via LIN-Fast-Mode**

For flash programming the transmission rate of the integrated LIN transceiver can be changed to maximum 115 kBaud via SPI command. A dedicated BROM routine of the XC885 takes care of periodically servicing the watchdog during this LIN-Fast-Mode. Further details are available in the XC885 User's Manual.



**Figure 20 LIN Flash mode SPI command**

### <span id="page-49-1"></span>**18.4 Thermal Resistance**

 $T_J = T_A + (P_D \times R_{thJA})$  (8)

- $T_{\text{J}}$  = Junction temperature [°C]
- $T_A$  = Ambient temperature [°C]
- $P_{\text{D}}$  = Total chip power dissipation [W]
- $P_{INT}$  = Chip internal power dissipation [W]
- $P_{\text{IO}}$  = Power dissipation caused by I/O currents [W]
- $R_{thJA}$  = Package thermal resistance [K/W]; junction-ambient

The total power dissipation can be calculated from:

 $P_{\text{D}} = P_{\text{INT}} + P_{\text{IO}}$  $= P_{\text{INT}} + P_{\text{IO}}$  (9)

### <span id="page-49-2"></span>**18.5 ESD Tests**

Tests for ESD robustness according to IEC61000-4-2 "gun test" (150pF, 330Ω) have been performed. The results and test condition are available in a test report.

### Table 15 ESD "GUN test"



<span id="page-49-3"></span>1) ESD susceptibility "ESD GUN" according LIN EMC 1.3 Test Specification, Section 4.3. (IEC 61000-4-2) -Tested by external test house (IBEE Zwickau, EMC Test report Nr. 09-09-07).



### **Package Outlines**

### <span id="page-50-0"></span>**19 Package Outlines**



**Figure 21 PG-DSO-28-38** (Plastic Dual Small Outline Package)

### **Green Product (RoHS compliant)**

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with government regulations the device is available as a green product. Green products are RoHS-Compliant (i.e Pb-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020).

For further information on alternative packages, please visit our website: **[http://www.infineon.com/packages](http://www.infineon.com/packages/)**. **Dimensions in mm** 



**Revision History**

### <span id="page-51-0"></span>**20 Revision History**



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